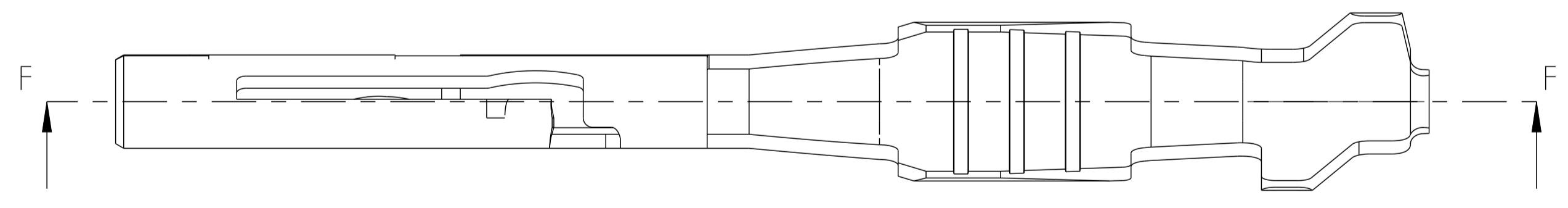
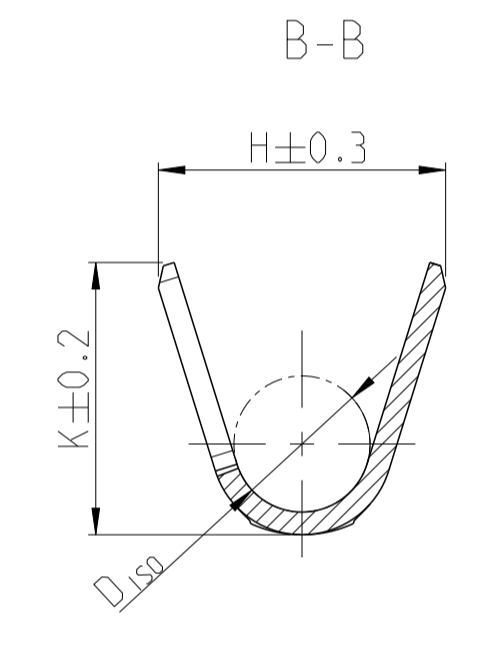
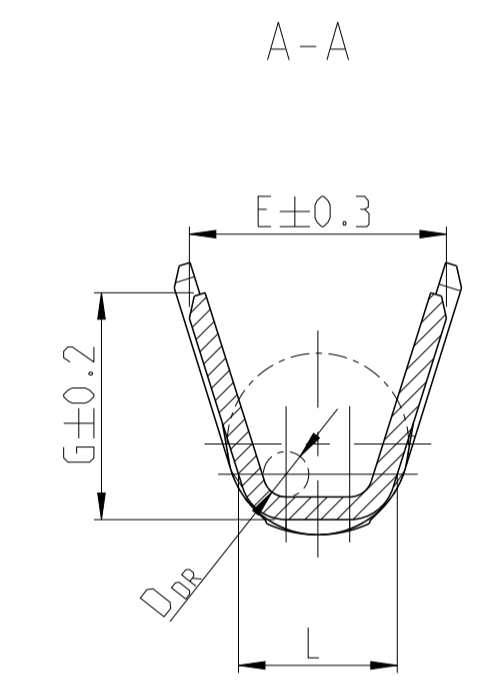
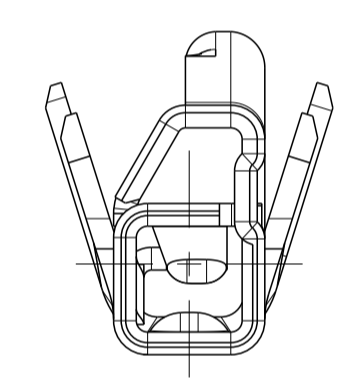
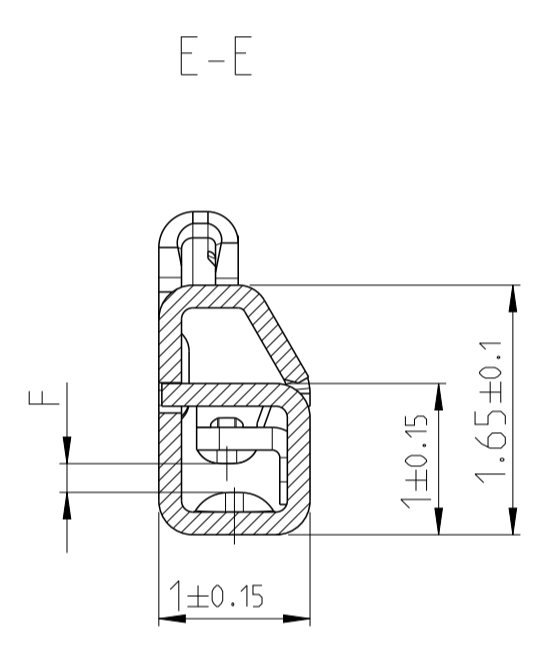
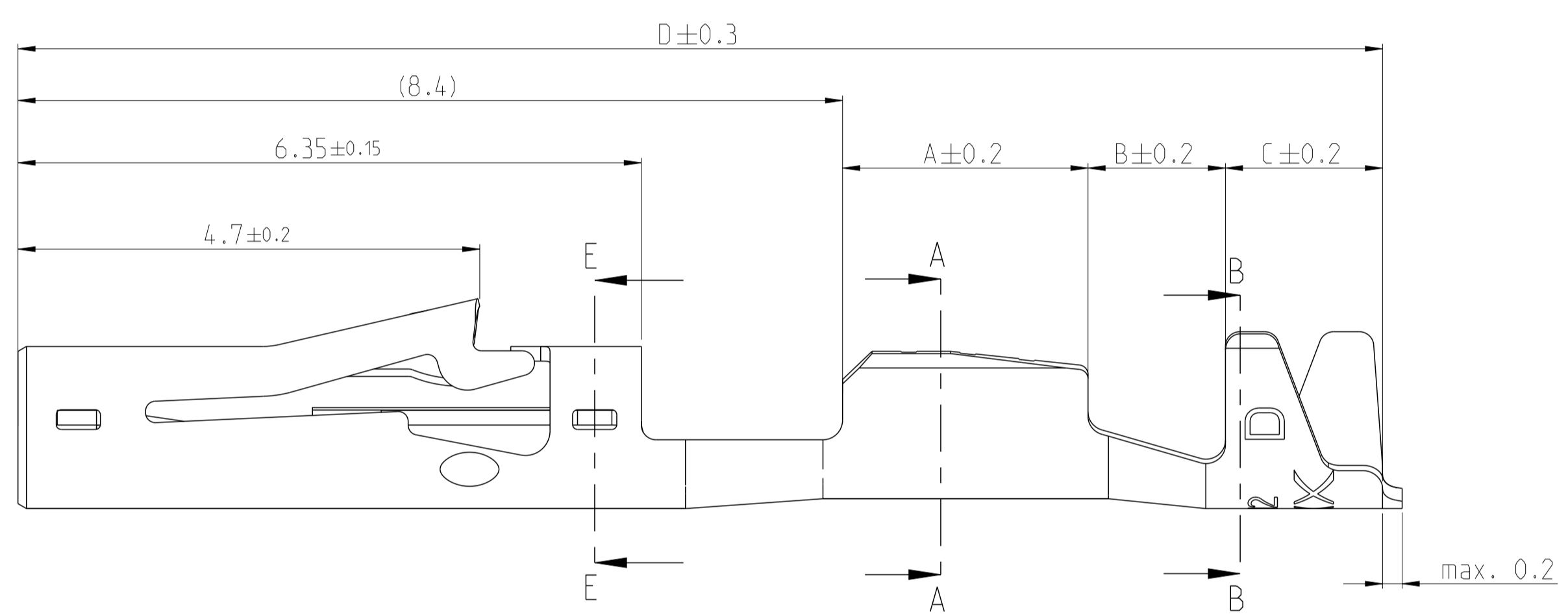
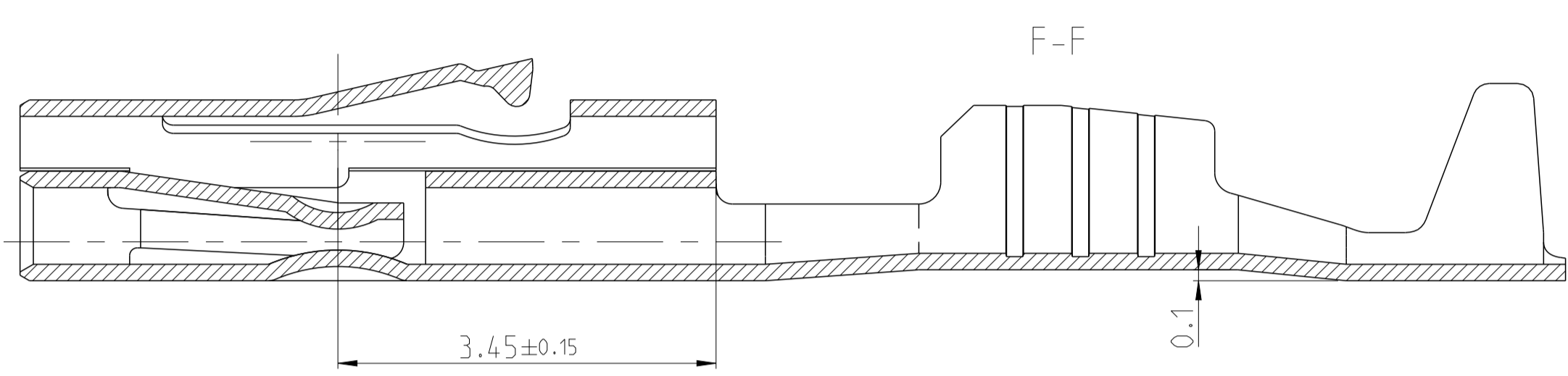
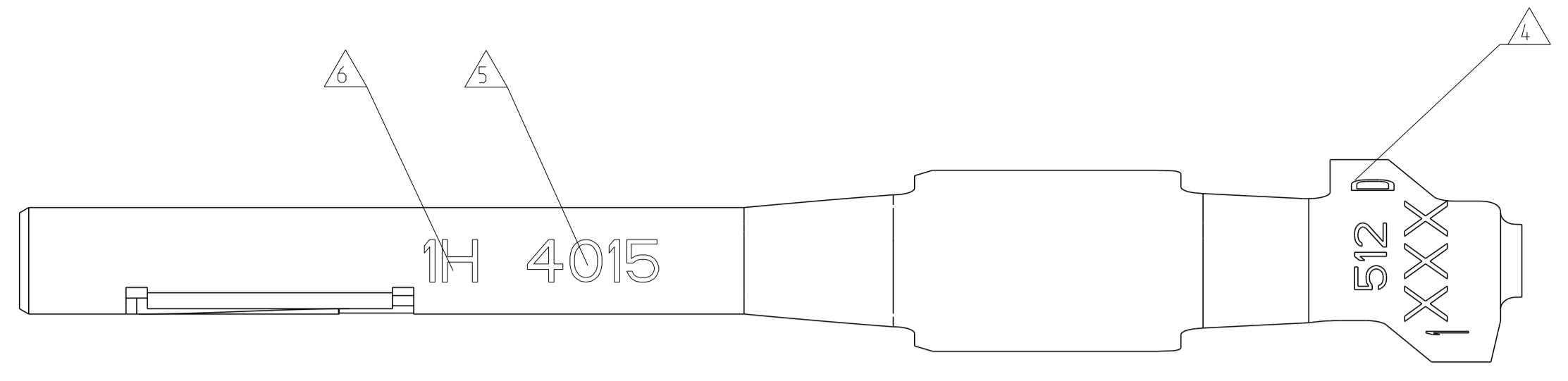
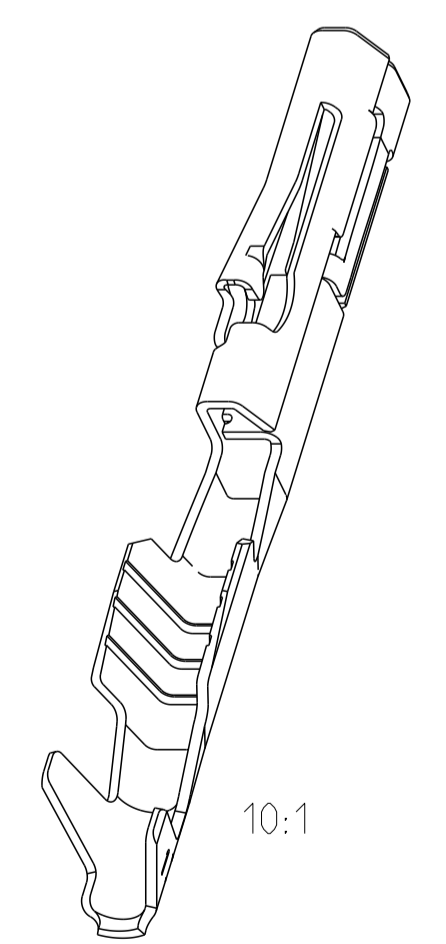


LOC	DIST	REVISIONS			
A1	-	REV.	DATE	DWN	APVD
PROJECT NR.:	E	ECR-12-001383	23JAN2012	MS	RJ
	E1	ECR-12-018001	16OCT2012	MS	RJ
	E2	ECR-13-010728	04JUL2013	MS	RJ
	F	ECR-16-000904	21JAN2016	HO.	LEIM



1 Buchsenkontakt/SOCKET CONTACT
 Material: siehe Tabelle/SEE CHART
 Oberfläche im Kontaktpunkt / SURFACE AT CONTACT-AREA:
 Sn: 0.8 ... 2.2 µm Sn
 Ag: 1.6 ... 5 µm Ag



TE BESTELL-NR. ORDER NO.	REV.	VERSION	Markierung MARKING	DGB WIRE SIZE RANGE [mm ²]	Material	OBERFLAECHE SURFACE	Gewicht WEIGHT [g]	F [mm]	Laenge LENGTH	Drahtcrimp WIRE CRIMP	Iso' crimp INSULATION CRIMP
2-1703930-2	F	HIGH PERFORMANCE	2H	0.22...0.35	CuNiSi	Ag	0.19±0.04	A = 2.5 B = 1.4 C = 1.6 D = 13.9	E = 1.7 G = 1.5 D _{DR} = 0.3 L = 1.05	H = 1.9 K = 1.9 D _{ISO} = 0.9	
2-1703930-1	E	Standard	2		CuSn8	Sn					0.19±0.04
1-1703930-2	F	HIGH PERFORMANCE	1H	0.13...0.17	CuNiSi	Ag	0.19±0.04	A = 2.5 B = 1.4 C = 1.6 D = 13.9	E = 1.6 G = 1.25 D _{DR} = 0.3 L = 0.9	H = 1.9 K = 1.8 D _{ISO} = 0.9	
1-1703930-1	E	Standard	1		CuSn8	Sn					0.19±0.04

Bemerkungen
NOTES

- 1 Massgebend ist der deutsche Text
ONLY THE GERMAN LANGUAGE VERSION SHALL BE BINDING
 - 2 Einzelheiten der Ausführung bleiben dem Hersteller ueberlassen
DETAILS OF DESIGN ARE LEFT TO MANUFACTURER
 - 3 Passend zu Kontaktsliff: TE 114-94000-1
SUITABLE TO CONTACT-PIN.
- 4 TE-Revision
TE REVISION
- 5 Datumscode (Woche/Jahr)
DATE-CODE (WEEK/YEAR)

THIS DRAWING IS A CONTROLLED DOCUMENT. DIMENSIONS: MASSENHEITEN: mm. TOLERANCES: UNLESS OTHERWISE SPECIFIED: ALLE DIMENSIONEN: mm. DIMENSIONS: mm. MATERIAL: -. FINISH/OBERFLAECHE/FARB: -. WEIGHT: -. CUSTOMER DRAWING.

DWN: S. G., 04SEP2007
CHK: C. Boemmel, 04SEP2007
APVD: J. Jetter, 04SEP2007

NAME: NanoMQS Buchsenkontakt SOCKET CONTACT

SIZE: A1 00779
SCALE: 20:1

RESTRICTED TO: NUR FÜR: -